

Amendments to the Claims:

This listing of claims will replace all prior versions, and listings, of claims in the application:

Listing of Claims:

1-3. (Canceled)

4. (Previously Presented) A method of etching an organic dielectric layer over a substrate, comprising:

placing a hard mask over the organic dielectric layer;

placing a patterned photoresist layer over the hard mask layer;

placing the substrate in an etching chamber;

providing an etchant gas comprising NH₃ into the etching chamber, wherein the NH₃ has a flow rate between 5 sccm to 1500 sccm;

generating a plasma from the NH₃, which selectively etches the organic dielectric layer with respect to the hardmask; and

simultaneously stripping the photo resist layer during the etching of the organic dielectric layer.

5. (Original) The method, as recited in claim 4, further comprising providing CH₃F while providing the etchant gas comprising NH₃.

6. (Canceled)

7. (Previously Presented) The method, as recited in claim 5, further comprising providing an etch with an etchant gas comprising CF₄, prior to the step of providing the etchant gas comprising NH₃.

8. (Original) The method, as recited in claim 7, wherein the etchant gas comprising CF₄, further comprises C₄F₈.

9. (Original) The method, as recited in claim 8, wherein the etchant gas comprising CF₄ further comprises O₂.

10. (Canceled)

11. (Previously Presented) The method, as recited in claim 4, wherein the organic dielectric layer is made of an organic low-k material, and wherein the simultaneous stripping completely strips the photoresist layer.

12. (Canceled)

13. (Previously Presented) A method of etching an organic low-k dielectric layer over a substrate, comprising:

placing a hard mask over the organic low-k dielectric layer;

placing a patterned photoresist layer over the hard mask layer;

placing the substrate in an etching chamber;

providing an etchant gas comprising NH₃ into the etching chamber;

generating a plasma from the NH₃, which is able to selectively etch [etches] the organic low-k dielectric layer with respect to the hard mask and strips the photoresist layer;

selectively etching the organic low-k dielectric layer with respect to the hardmask; and

simultaneously stripping the photo resist layer during the selective etching of the organic low-k dielectric layer.

14-19. (Canceled)

20. (Previously Presented) The method, as recited in claim 13, wherein the NH₃ has a flow rate, wherein the flow rate of NH₃ is from about 100 sccm to about 1000 sccm.

21. (Previously Presented) The method, as recited in claim 13, wherein the NH₃ has a flow rate from about 300 sccm to about 800 sccm.

22. (Previously Presented) The method, as recited in claim 21, further comprising maintaining the substrate at a temperature between about 10° C to about 40° C during etching of the organic dielectric layer.

23. (Canceled)

24. (Previously Presented) A method of etching an organic dielectric layer disposed below a hardmask layer and over a substrate, comprising:

placing the substrate in an etching chamber;

providing an etchant gas comprising NH₃ into the etching chamber with a flow rate from about 300 sccm to about 800 sccm;

generating a plasma from the NH₃, which etches the organic dielectric layer; and

maintaining the substrate at a temperature between about 10° C to about 40° C during the etching of the organic dielectric layer.

25. (Previously Presented) The method, as recited in claim 1, further comprising providing a bias power of between about 0 W and 100 W during etching of the organic dielectric layer.

26. (Previously Presented) The method, as recited in claim 13, further comprising providing a bias power of between about 0 W and 100 W during etching of the organic low-k dielectric layer.

27. (Previously Presented) The method, as recited in claim 13, further comprising:

placing an etch stop layer over the organic low-k dielectric layer;

placing a second organic low-k dielectric layer over the etch stop layer, wherein the second organic low-k dielectric layer is between the organic low-k dielectric layer and the hardmask.

28. (Previously Presented) The method, as recited in claim 27, further comprising etching the second organic low-k dielectric layer with a first etch, wherein the first etch provides a bias power of between about 250 W to about 2500 W before selectively etching the organic low-k dielectric layer.

29. (Previously Presented) The method, as recited in claim 28, further comprising providing a bias power of between about 0 W and 100 W during etching of the organic dielectric layer.

30. (Previously Presented) The method, as recited in claim 29, further comprising providing an etchant gas comprising CF₄ for the etching the second low-k organic dielectric layer.

31. (Previously Presented) The method, as recited in claim 30, wherein the etchant gas comprising CF₄ further comprises C₄F₈.

32. (Previously Presented) The method, as recited in claim 31, wherein the etchant gas comprising NH₃ uses NH₃ alone as the etchant.

33. (Previously Presented) The method, as recited in claim 13, wherein the simultaneous stripping completely strips the photoresist.

34. (Previously Presented) The method, as recited in claim 13, wherein the etchant gas comprising NH₃ uses NH₃ alone as the etchant.